

**Notice of References Cited**

Application/Control No

09/990,862

Applicant(s)/Patent Under  
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HSIEH ET AL.

Examiner

Thao X Le

Art Unit

2814

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,596,214	01-1997	Endo, Nobuhiro	257/324
	B	US-5,768,192	06-1998	Eitan, Boaz	365/185.24
	C	US-6,255,121	07-2001	Arita et al.	438/3
	D	US-2002/0142569	10-2002	Cahng et al.	438/585
	E	US-2001/0044187	11-2001	Joo et al.	438/264
	F	US-6,248,675	06-2001	Xiang et al.	438/166
	G	US-6,207,589	03-2001	Ma et al.	438/785
	H	US-2002/0164855	11-2002	Pan et al.	438/257
	I	US-2002/0086548	07-2002	Chang, Kent Kuohua	438/724
	J	US-6,348,380	02-2002	Weimer et al.	438/257
	K	US-5,168,334	12-1992	Mitchell et al.	257/324
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-007230 /	01-2001	Japan	Komori et al.	H01L 21/8247
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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